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Title: ETCHING OF HIGH ASPECT RATIO STRUCTURES

U.S. Patent References				
Examiner Initials	Patent No.	Issue Date	Name	Filing Date
<i>TA</i>	4,717,448	01-05-1988	Cox et al.	10-09-1986
	5,100,505	03-31-1992	Cathey, Jr.	10-18-1990
	5,185,058	02-09-1993	Cathey, Jr.	01-29-1991
	5,227,750	01-11-1994	Frank	03-05-1992
	5,296,095	03-22-1994	Nabeshima et al.	10-30-1991
	5,409,563	04-25-1995	Cathey	02-26-1993
	5,423,941	06-13-1995	Komura et al.	11-17-1993
	5,470,768	11-28-1995	Yanai et al.	08-05-1993
	5,472,564	12-05-1995	Nakamura et al.	08-11-1993
	5,492,597	02-20-1996	Keller	05-13-1994
	5,522,966	06-04-1996	Komura et al.	11-17-1993
	5,578,161	11-26-1996	Auda	04-15-1992
	5,605,603	02-25-1997	Grimard et al.	03-29-1995
	5,685,950	11-11-1997	Sato	07-15-1996
	5,756,216	05-26-1998	Becker et al.	02-12-1997
	5,756,401	05-26-1998	Iizuka	03-08-1993
	5,759,922	06-02-1998	Donohoe	01-10-1997
	5,783,100	07-21-1998	Blalock et al.	11-19-1996
	5,843,226	12-01-1998	Zhao et al.	07-16-1996
	5,869,845	02-09-1999	Vander Wagt et al.	06-26-1996
	5,871,659	02-16-1999	Sakano et al.	06-18-1996
	5,882,535	03-16-1999	Stocks et al.	02-04-1997
	5,906,950	05-25-1999	Keller et al.	07-21-1997
	6,020,270	02-01-2000	Wong et al.	08-14-1998
	6,025,276	02-15-2000	Donohoe et al.	09-03-1998
	6,051,863	04-18-2000	Hause et al.	11-21-1998
	6,069,091	05-30-2000	Chang et al.	12-29-1998
	6,074,957	06-13-2000	Donohoe et al.	02-26-1998
	6,093,655	07-25-2000	Donohoe et al.	02-12-1998
	6,123,862	09-26-2000	Donohoe et al.	06-17-1998
	6,163,066	12-19-2000	Forbes et al.	08-24-1998
	6,180,533	06-30-2001	Jain et al.	04-07-2000
<i>TA</i>	6,204,143	03-20-2001	Roberts et al.	04-15-1999

RECEIVED

Foreign Patent References				
Examiner Initials	Foreign Patent		Name	Publication Date
	Country	No.		T?

Other References	
Examiner Initials	Author, Title, Date, Pages, etc.

Examiner Signature	<i>AyerG</i>	Date Considered	3/16/03
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